

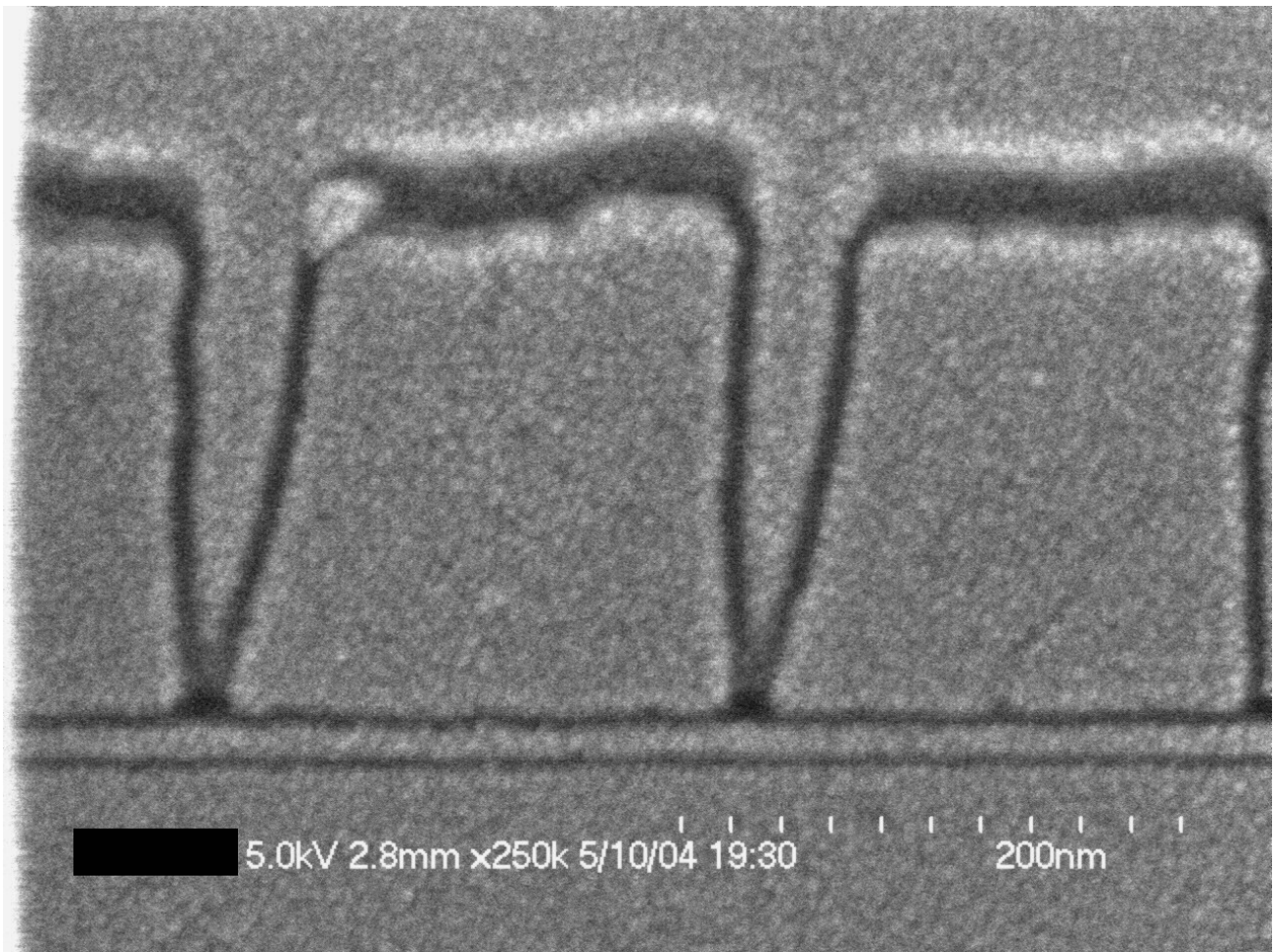
# Evactron® RF Plasma Cleaning Improves SEM Performance

## Case study: Hitachi S4700 FE SEM

This SEM is a general use instrument at a major semiconductor company. It has been dry pumped since it was purchased in 1998. Metrology on the instrument is checked weekly against a MagiCal® reference standard. Resolution had been about 6 nm @ 15 KV before Evactron cleaning.

Specimen is an IC wafer cross section with 10 nm features that was sputtered with Pt coating before examination.

The Evactron was installed on May 7, 2004, and the instrument given 3 - five minute cleanings as part of the installation. After cleaning, all users were asked to send-in any pictures showing improved performance. This one blew us away! Pt particles as small as 2-3 nm can be seen! Another user thought the picture had been taken on the high performance S5200 in the same lab.



“Evactron Anti-Contaminators are the one accessory you can buy that will actually improve the performance of the SEM.” - Dept. Mgr.

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